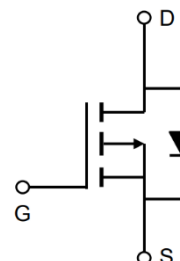


-18V P-Channel Enhancement Mode MOSFET

Description

The AP20P01BF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

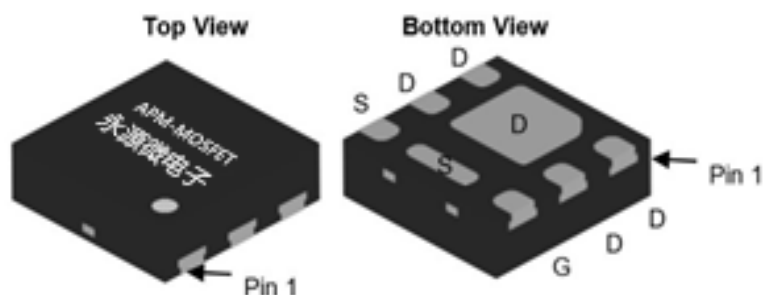
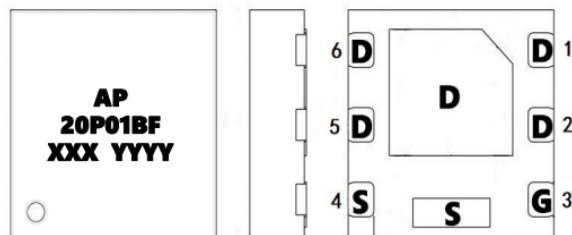
$V_{DS} = -18V$ $I_D = -20A$

$R_{DS(ON)} < 18m\Omega$ @ $V_{GS}=10V$ (Type: 12m Ω)

$R_{DS(ON)} < 23m\Omega$ @ $V_{GS}=4.5V$ (Type: 14m Ω)

Application

Electronic cigarette
Load switch



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP20P01BF	QFN2*2-6L	AP20P01BF XXX YYYY	3000

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-Source Voltage	-18	V
V_{GSS}	Gate-Source Voltage	± 12	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	-20	A
$I_D@T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	-10.6	A
IDM	Pulsed Drain Current ^{note1}	-36	A
$P_D@T_C=25^\circ\text{C}$	Power Dissipation	1.6	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	125	$^\circ\text{C/W}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

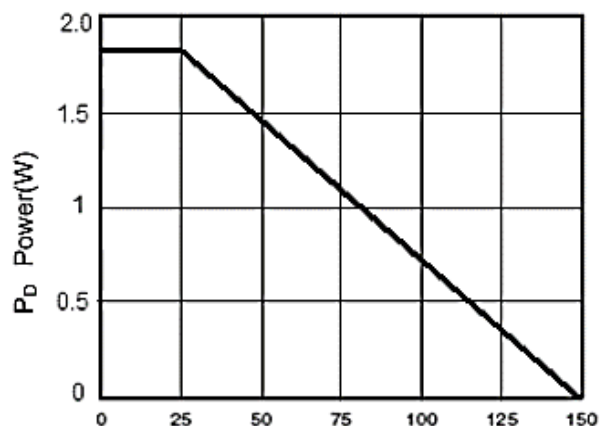
-18V P-Channel Enhancement Mode MOSFET
Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-12	-18	-	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS}=-12V, V_{GS}=0V,$	-	-	-1	μA
IGSS	Gate to Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 12V$	-	-	± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-0.5	-0.65	-1.0	V
RDS(on)	Static Drain-Source on-Resistance note2	$V_{GS}=-10V, I_D=-6.0A$	-	12	18	m Ω
RDS(on)	Static Drain-Source on-Resistance note2	$V_{GS}=-4.5V, I_D=-5.2A$	-	14	23	m Ω
RDS(on)	Static Drain-Source on-Resistance note2	$V_{GS}=-2.5V, I_D=-4.2A$		20	35	m Ω
Ciss	Input Capacitance	$V_{DS}=-6V, V_{GS}=0V$ $f=1.0\text{MHz}$	-	1100	-	pF
Coss	Output Capacitance		-	390	-	pF
Crss	Reverse Transfer Capacitance		-	300	-	pF
Qg	Total Gate Charge	$V_{DS}=-4V, I_D=-4.1A,$ $V_{GS}=-4.5V$	-	11.5		nC
Qgs	Gate-Source Charge		-	1.5	-	nC
Qgd	Gate-Drain("Miller") Charge		-	3.2	-	nC
td(on)	Turn-on Delay Time	$V_{DD}=-4V, I_D=-3.3A,$ $R_G=1.0\Omega, V_{GEN}=-4.5V,$ $R_L=1.2\Omega$	-	25	-	ns
t _r	Turn-on Rise Time		-	45	-	ns
td(off)	Turn-off Delay Time		-	72	-	ns
t _f	Turn-off Fall Time		-	60	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	-6.0	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-16	A
VSD	Drain to Source Diode Forward Voltage	$V_{GS}=0V, I_S=-4.1A$	-	-	-1.2	V
t _{rr}	Reverse Recovery Time	$V_{GS}=0V, I_S=-4.1A,$ $di/dt=100A/\mu s$	-	20	-	ns
Q _{rr}	Reverse Recovery Charge		-	9	-	nC

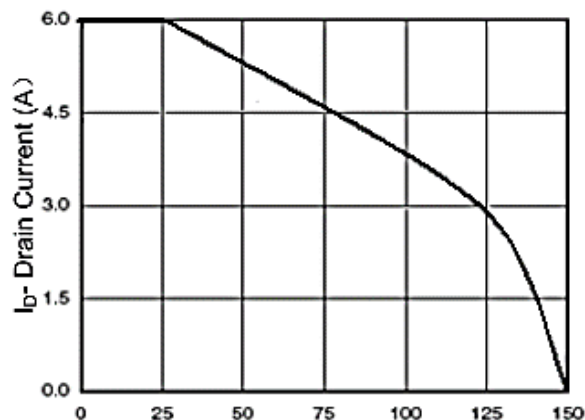
Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3、The power dissipation is limited by 150 $^{\circ}\text{C}$ junction temperature
- 4、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

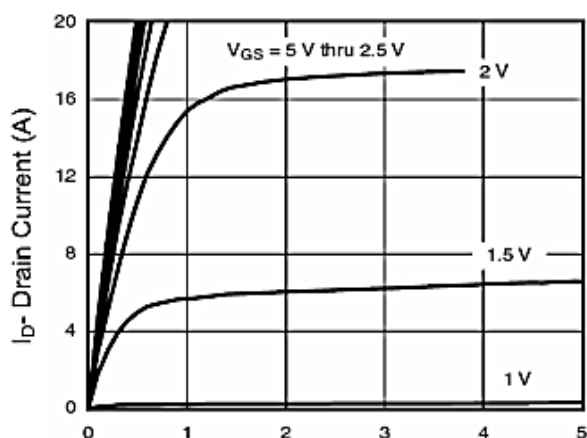
Typical Characteristics



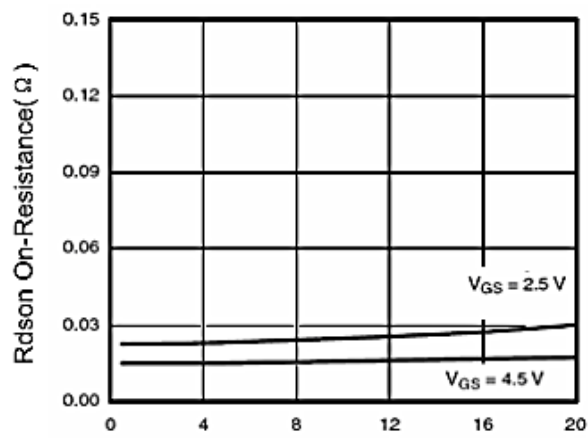
T_J -Junction Temperature (°C)
Figure 1 Power Dissipation



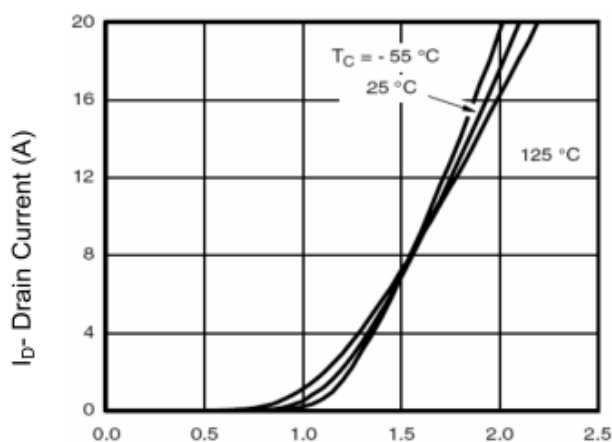
T_J -Junction Temperature (°C)
Figure 2 Drain Current



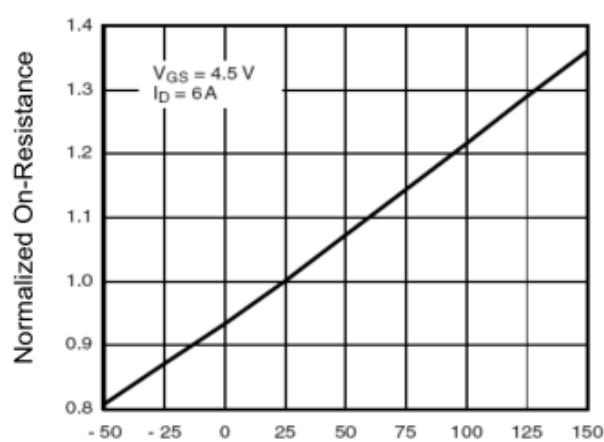
V_{DS} Drain-Source Voltage (V)
Figure 3 Output Characteristics



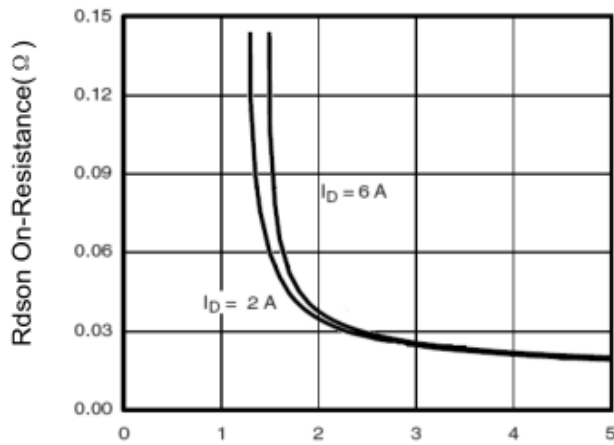
I_D -Drain Current (A)
Figure 4 Drain-Source On-Resistance



V_{GS} Gate-Source Voltage (V)
Figure 5 Transfer Characteristics

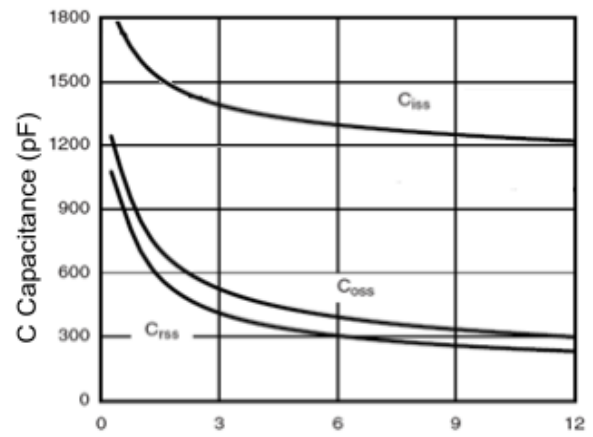


T_J -Junction Temperature (°C)
Figure 6 Drain-Source On-Resistance



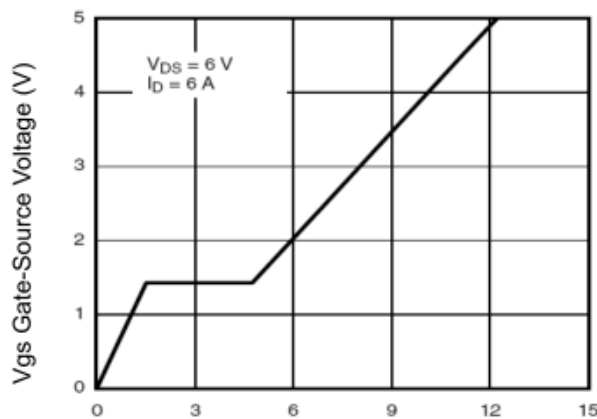
Vgs Gate-Source Voltage (V)

Figure 7 Rdson vs Vgs



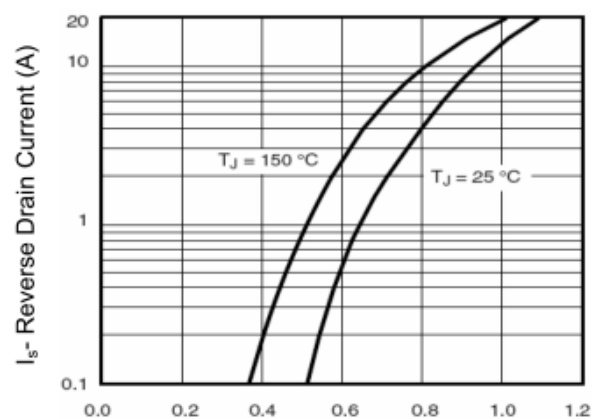
Vds Drain-Source Voltage (V)

Figure 8 Capacitance vs Vds



Qg Gate Charge (nC)

Figure 9 Gate Charge



Vsd Source-Drain Voltage (V)

Figure 10 Source- Drain Diode Forward

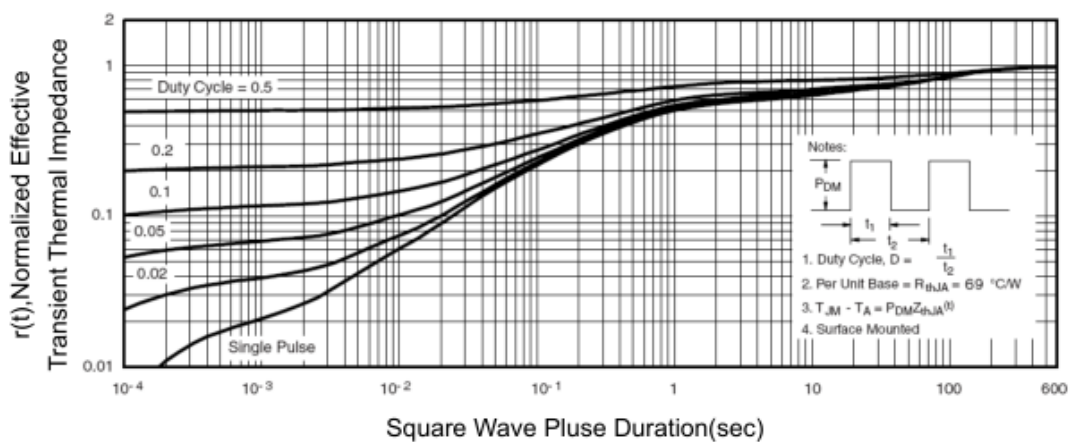
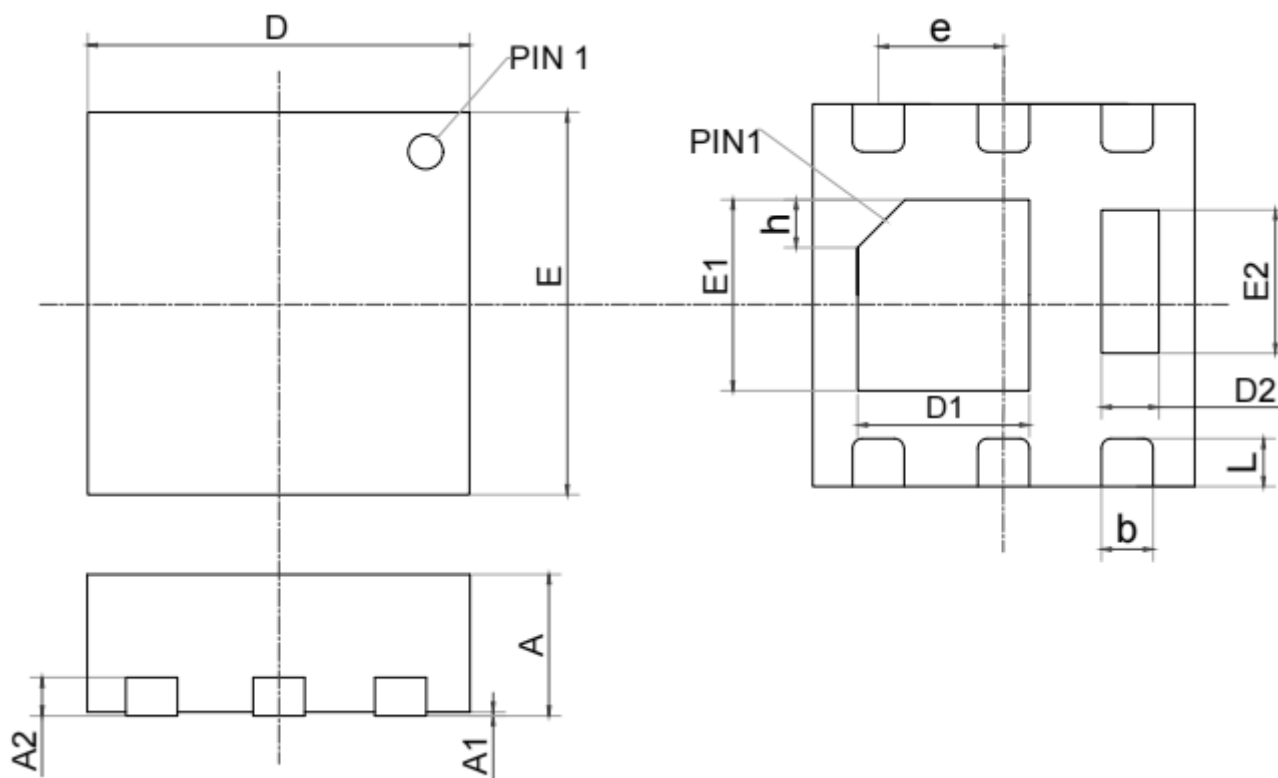


Figure 12 Normalized Maximum Transient Thermal Impedance

Package Mechanical Data: QFN2*2-6L



Symbol			
	Min	Nom	Max
A	0.70	0.75	0.80
A1	--	0.02	0.05
A2	0.18	0.20	0.25
b	0.20	0.27	0.34
D	1.95	2.00	2.05
E	1.95	2.00	2.05
D1	0.80	0.90	1.00
E1	0.90	1.00	1.10
D2	0.20	0.30	0.40
E2	0.65	0.75	0.85
L	0.20	0.25	0.35
h	0.20	0.25	0.30
e	0.65 BSC		

-18V P-Channel Enhancement Mode MOSFET**Attention**

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-18V P-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2020/9/8	Initial release

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